

FORM PTO-1449 (REV. 8-00)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. NIT-163-02	SERIAL NO. 10/075,283
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT M. IWAYAMA et al	
		FILING DATE February 15, 2002	GROUP 2175

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA 5,590,319	12/31/96	Cohen et al			
	AB 5,987,460	11/1999	Niwa et al			
	AC 5,926,811	07/1999	Miller et al			
	AD 5,870,740	02/1999	Miller et al			
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

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FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	AL 64-74210	03/20/89	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM 93/37499	08/27/98	WO PCT			<input type="checkbox"/>	<input type="checkbox"/>
	AN 10-74210	03/17/98	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
	AO 11-85786	03/30/99	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
	AP 10-254887	09/25/98	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	B. Velez et al, "Fast and Effective Query Refinement", Annual International ACM-SIGIR Conference on Research and Development in Information Retrieval, US, New York, NY, July 27, 1997, pp. 6-15.
	AS	
	AT	

EXAMINER	DATE CONSIDERED
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. NIT-163-02	SERIAL NO. 10/075,283
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	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AL	8-287103	11/01/96	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AM	9-62693	03/07/97	Japanese Laid-Open Patent			<input type="checkbox"/>	<input type="checkbox"/>
AN						<input type="checkbox"/>	<input type="checkbox"/>
AO						<input type="checkbox"/>	<input type="checkbox"/>
AP						<input type="checkbox"/>	<input type="checkbox"/>

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